

## **MODEL 1051**

## **TEM Mill**

A state-of-the-art ion milling and polishing system offering reliable, high performance specimen preparation. It consistently produces high-quality transmission electron microscopy (TEM) specimens with large electron transparent areas from a wide variety of materials.

## Model 1051 TEM Mill specifications

lon sources	Two TrueFocus ion sources
	Variable energy (100 eV to 10 kV) operation
	Beam current density up to 10 mA/cm <sup>2</sup>
	Milling angle range of -15 to +10°
	Choice of single or dual ion source operation
	Independent ion source energy control
	Manual or motorized (optional) ion source angle adjustment
	Adjustable spot size
	Faraday cups for the direct measurement of beam current from each ion source; allows optimization and adjustment of the ion source parameters for specific applications
Specimen holder	Designed for improved specimen handling and thermal properties; includes loading station
	Holder clamping mechanism allows for simple specimen loading and double-sided milling to 0° without shadowing
	Specimen holder and loading station with x-y adjustment capabilities (optional)
Specimen stage	Specimen size: 3 mm diameter x 250 µm thick
	360° specimen rotation with variable rotation speed and beam sequencing
	Specimen rocking
	Magnetic encoder provides absolute positioning accuracy

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Specimen cooling (optional)	Liquid nitrogen conductive cooling with integral dewar and automatic temperature interlocks	
	Dewar access positioned close to instrument operator	
	Ability to program and maintain a specific temperature between ambient and cryogenic	
	Choice of:	
	<ul> <li>Standard dewar capacity (3 to 5 hours of cryo conditions)</li> </ul>	
	<ul> <li>Extended dewar capacity (18+ hours of cryo conditions)</li> </ul>	
Automatic termination	Automatic termination by time, temperature, or laser photodetector (optional)	
Vacuum system	Turbomolecular drag pump and an oil-free, multi-stage diaphragm pump	
	Vacuum sensing with a cold cathode, full-range gauge	
Vacuum or inert gas transfer capsule (optional)	Allows transfer or storage of specimen at vacuum or in an inert gas environment	
Process gas	UHP argon (99.999%); nominal 15 psi delivery pressure required	
	Automatic gas control using two mass flow controllers	
User interface	Instrument operation controlled via 10-inch, adjustable touch screen	
	Stack light indicator for determining milling operations status from a distance (optional)	
Microscope (optional)	Load lock window accommodates either a:	
	<ul> <li>7 to 45 X stereo microscope attachment for direct specimen observation</li> </ul>	
	<ul> <li>1,960 X high-magnification microscope and CMOS (complementary metal oxide semiconductor) camera system for site-specific image acquisition and display</li> </ul>	

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In situ viewing/imaging	Specimen can be monitored in situ in the milling position when using either the stereo or the high-magnification microscope	
	Viewing window protected by a programmable shutter that prevents buildup of sputtered material and preserves the ability to observe the specimen in situ	
Specimen illumination	A light positioned beneath the specimen provides user adjustable, transmitted specimen illumination	
	Both the high-magnification and stereo microscopes have light sources that provide top-down, user adjustable, reflected sample illumination	
Enclosure	Width (includes room on either side for service access: 50 in. (127 cm)	
	Height:	
	<ul> <li>Minimum height (without microscope or stack light options): 32 in. (61 cm)</li> </ul>	
	<ul> <li>Maximum height (with stack light option):</li> <li>38 in. (77 cm)</li> </ul>	
	Depth (includes room for service access and exhaust fan air flow): 40 in. (102 cm)	
	Enclosure design offers easy access to internal components when performing maintenance tasks	
Weight	161 lb. (73 kg)	
Power	100/120/220/240 VAC, 50/60 Hz, 720 W	
Warranty	One year	

